

ISW
PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/613,374 Confirmation No. 7181
Applicants : S. Datta et al.
Filed : July 3, 2003
TC/A.U. : 1711
Examiner : Nathan M. Nutter

Docket No. : 1998B037A/2
Customer No. : 1473

Mail Stop Amendment
Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

New York, New York 10020
October 6, 2004

**TRANSMITTAL LETTER FOR
INFORMATION DISCLOSURE STATEMENT**

Sir:

Transmitted herewith is an Information Disclosure Statement Pursuant to 37
C.F.R. § 1.97(c)(2) in the above-identified application.

The Office's PAIR System lists a Notice of Allowability dated September 14,
2004, in the above-identified application. To date, Applicants have not received this Notice by
mail. Furthermore, there is no indication in PAIR that the Notice has been mailed or that a
Notice of Allowance has been issued or mailed.

Thus, Applicants submit this Statement pursuant to 37 C.F.R. § 1.97(c)(2) because it is more than three months from the application filing date and after the mailing date of the March 31, 2004 Office Action, but before the mailing date of (a) a final action under 37 C.F.R. § 1.113, (b) a notice of allowance under 37 C.F.R. § 1.311, or (c) an action that otherwise closes prosecution in the application.

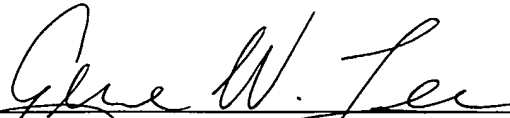
In accordance with 37 C.F.R. § 1.97(c)(2), Applicants have enclosed a check in the amount of \$180.00, in payment for fees required in connection with the accompanying Information Disclosure Statement under 37 C.F.R. § 1.17(p). A duplicate copy of this letter is transmitted herewith.

The Director is hereby authorized to charge payment of any additional fees in connection with the papers transmitted herewith, or to credit any overpayment of same, to Deposit Account No. 06-1075. A duplicate copy of this transmittal letter is transmitted herewith.

If Applicants are mistaken in concluding that this Information Disclosure Statement is properly submitted pursuant to 37 C.F.R. § 1.97(c)(2), then Applicants request that this submission be treated as a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application, and the Director is hereby authorized to charge payment of the additional fee required under 37 C.F.R. § 1.17(e) to Deposit Account No. 06-1075. A duplicate copy of this transmittal letter is transmitted herewith. If this submission is

treated as an RCE, Applicants request that the accompanying Information Disclosure Statement Pursuant to 37 C.F.R. § 1.97(e)(2), Form PTO-1449 and the cited documents be considered in the continued examination.

Respectfully submitted,



Eric C. Woglom (Reg. No. 25,445)

Glenn A. Ousterhout (Reg. No. 30,410)

Gene W. Lee (Reg. No. 55,369)

Attorneys for Applicants

Wendy A. Petka (Reg. No. 53,459)

Agent for Applicants

c/o FISH & NEAVE LLP

Customer No. 1473

1251 Avenue of the Americas

New York, New York 10020-1104

Tel.: (212) 596-9000



PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/613,374 Confirmation No. 7181
Applicants : S. Datta et al.
Filed : July 3, 2003
TC/A.U. : 1711
Examiner : Nathan M. Nutter

Docket No. : 1998B037A/2
Customer No. : 1473

Mail Stop Amendment
Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

New York, New York 10020
October 6, 2004

**INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. § 1.97(c)(2)**

Sir:

Applicants are filing this Information Disclosure Statement pursuant to 37 C.F.R. § 1.97(c)(2). A check in the amount of \$180.00, as prescribed by 37 C.F.R. § 1.17(p), is enclosed.

The Office's PAIR System lists a Notice of Allowability dated September 14, 2004, in the above-identified application. To date, Applicants have not received this Notice by mail. Furthermore, there is no indication in PAIR that the Notice has been mailed or that a Notice of Allowance has been issued or mailed. Consequently, this Information Disclosure Statement is submitted pursuant to 37 C.F.R. § 1.97(c)(2).

10/08/2004 SSANDARA 00000005 10613374

01 FC:1806

180.00 0P

Pursuant to 37 C.F.R. §§ 1.56 and 1.97, Applicants hereby make the following information and documents of record in the above-identified patent application.

On April 22, 2004, Applicants filed Requests for Interferences with Tau et al. application no. 10/289,122 (“the Tau ‘168 application”) and Stevens et al. application no. 10/289,122 (“the Stevens ‘122 application”) in the above-identified application.

Applicants are filing this Information Disclosure Statement to make of record those documents that were cited and considered in the Tau ‘168 and Stevens ‘122 applications. Applicants’ claims 32-48 were presented for the purpose of provoking interferences with the Tau ‘168 and Stevens ‘122 applications. Applicants’ claims 32-48 are patterned after and narrower than the corresponding claims in the Tau ‘168 and Stevens ‘122 applications, which were allowed over these cited references.

Applicants also are filing this Information Disclosure Statement to make of record documents not initialed by the Examiner in the Information Disclosure Statement previously submitted in the above-identified application on January 20, 2004.

In addition, Applicants are making of record four references cited by Examiner Ling-Siu Choi in Stevens et al. application no. 10/139,786 (“the Stevens ‘786 application”).

The Stevens ‘786 application is related to the Tau ‘168 and Stevens ‘122 applications, and the real-party-in-interest for all three applications is The Dow Chemical Company (“Dow”). The Stevens ‘786 application relates to propylene/ethylene copolymers

having certain specified properties, including (1) ^{13}C NMR peaks corresponding to a regio error, (2) DSC melting behavior, (3) gamma-form crystal content determined by X-ray diffraction, (4) skewness index and (5) B-value. The Tau '168 and Stevens '122 applications relate to films and impact resistant blends, respectively, that include propylene/ethylene copolymers having some of the same specified properties.

During the prosecution of the Stevens '786 application, in an Office Action mailed December 8, 2003, Examiner Choi made rejections under 35 U.S.C. §§ 102 and 103 of several of the pending claims over Imuta et al. U.S. patent 5,504,172, Cozewith et al. U.S. patent application publication 2002/0004575A1 (published on January 10, 2002), Timmers et al. U.S. patent 5,972,822, and Devore et al. U.S. patent 5,556,928. (A copy of the December 8, 2003 Office Action is provided herewith as Appendix A). Each of the four references were cited as disclosing ethylene/propylene copolymers but as being silent on the specified properties in the rejected claims of the Stevens '786 application. Eventually, in the Stevens '786 application, claims to a propylene/ethylene copolymer were allowed (claims 1 and 6-15), where each claim required the copolymer to be "characterized as having ^{13}C NMR peaks corresponding to a regio-error at about 14.6 and about 15.7 ppm, the peaks of about equal intensity."

The three patent references mentioned in the preceding paragraph were cited by Dow in the prosecution of both the Tau '168 and Stevens '122 applications, were considered by the Examiner in those applications, and are listed below. The Cozewith et al. U.S. patent

publication, commonly assigned with this application, is not of record in either the Tau '168 or Stevens '122 application.

In addition, IDS's filed on July 17, 2003, in both the Tau '168 and Stevens '122 applications, cited two references: (1) Job et al. U.S. patent 5,134,209, and (3) a "News Release, Japan Polychem Launches WINTEC Metallocene-Based PP Random Copolymer, October 25, 2001, <http://www.m-kagaku.co.jp/english/rel/2001/102501.htm>." The IDS's (copies attached as Appendices B and C) stated:

The WINTEC[®] copolymers of Japan Polychem are believed to have a B-value of greater than 1.4. However, these copolymers are believed to have reigo-errors at 17 ppm, not at 14.6 and 15.7 ppm.

The polypropylene resins of the first three examples of USP 5,134,209 are believed to have a skewness index, S_{ix} , greater than about -1.20. However, these polypropylene resins are not believed to have regio-errors at 14.6 and 15.7 ppm.

These two references were considered by the Examiner in the prosecution of both the Tau '168 and Stevens '122 applications, and are listed below. Applicants note that the Japan Polychem news release, dated October 25, 2001, is well after Applicants' earliest effective filing date of July 1, 1998.

As noted above, the remainder of the references cited below and listed in the accompanying Form PTO-1449 are documents that were cited and considered in the Tau '168 and Stevens '122 applications. Applicants' claims 32-48 are patterned after and narrower than the corresponding claims in the Tau '168 and Stevens '122 applications, which were allowed over these cited references.

U.S. PATENTS AND PUBLISHED APPLICATIONS

<u>Inventor(s)</u>	<u>Patent/Application No.</u>	<u>Issue/Publication Date</u>
Anderson et al.	4,076,698	February 28, 1978
Kaminsky et al.	4,542,199	September 17, 1985
Jenkins, III et al.	4,543,399	September 24, 1985
Kaminsky et al.	4,544,762	October 1, 1985
Jenkins, III et al.	4,588,790	May 13, 1986
McKinney et al.	4,599,392	July 8, 1986
Miya et al.	4,874,880	October 17, 1989
Crapo et al.	4,960,878	October 2, 1990
McKinney et al.	4,988,781	January 29, 1991
Schmidt et al.	5,015,749	May 14, 1991
Chinh et al.	5,028,670	July 2, 1991
Lo et al.	5,032,562	July 16, 1991
Sangokoya	5,041,583	August 20, 1991
Crapo et al.	5,041,584	August 20, 1991
Deavenport et al.	5,041,585	August 20, 1991
Young	5,044,438	September 3, 1991
Canich et al.	5,057,475	October 15, 1991
Stevens et al.	5,064,802	November 12, 1991
Brady, III et al.	5,093,415	March 3, 1992
Canich	5,096,867	March 17, 1992
Bailly et al.	5,106,804	April 21, 1992
Stevens et al.	5,132,380	July 21, 1992
Job et al.	5,134,209	July 28, 1992
Hlatky et al.	5,153,157	October 6, 1992
Turner et al.	5,198,401	March 30, 1993
Tsutsui et al.	5,218,071	June 8, 1993
Lai et al.	5,272,236	December 21, 1993
Lai et al.	5,278,272	January 11, 1994
Siedle et al.	5,296,433	March 22, 1994
Welborn, Jr. et al.	5,324,800	June 28, 1994
Neithamer et al.	5,350,723	September 27, 1994
DeChellis et al.	5,352,749	October 4, 1994
McKinney et al.	5,384,373	January 24, 1995
DeChellis et al.	5,405,922	April 11, 1995
Turner et al.	5,408,017	April 18, 1995
Turner	5,427,991	June 27, 1995
Griffin et al.	5,436,304	July 25, 1995
Bernier et al.	5,453,471	March 26, 1995

U.S. PATENTS AND PUBLISHED APPLICATIONS

<u>Inventor(s)</u>	<u>Patent/Application No.</u>	<u>Issue/Publication Date</u>
Song et al.	5,461,123	October 24, 1995
Griffin et al.	5,462,999	October 31, 1995
Nowlin et al.	5,473,028	December 5, 1995
Crowther et al.	5,504,049	April 2, 1996
Imuta et al.	5,504,172	April 2, 1996
Chinh et al.	5,541,270	July 30, 1996
Chinh	5,556,238	September 17, 1996
Devore et al.	5,556,928	September 17, 1996
Turner	5,599,761	February 4, 1997
Cheruvu et al.	5,608,019	March 4, 1997
Eisinger et al.	5,616,661	April 1, 1997
Timmers et al.	5,616,664	April 1, 1997
Langhauser et al.	5,621,127	April 15, 1997
Devore et al.	5,625,087	April 29, 1997
Nagy et al.	5,637,660	June 10, 1997
Chum et al.	5,685,128	November 11, 1997
Timmers	5,703,187	December 30, 1997
Rosen et al.	5,703,257	December 30, 1997
Alt et al.	5,710,224	January 20, 1998
LaPointe et al.	5,721,185	February 24, 1998
Smith et al.	5,728,855	March 17, 1998
Sangokoya	5,731,253	March 24, 1998
Turner et al.	5,767,208	June 16, 1998
Asanuma et al.	5,840,389	November 24, 1998
Saito et al.	5,874,505	February 23, 1999
Hwang et al.	5,883,188	March 16, 1999
Spencer et al.	5,883,204	March 16, 1999
Turner et al.	5,907,021	May 25, 1999
Rosen et al.	5,919,983	July 6, 1999
McCullough et al.	5,962,714	October 5, 1999
Stephan et al.	5,965,677	October 12, 1999
McAdon et al.	5,965,756	October 12, 1999
Timmers et al.	5,972,822	October 26, 1999
Kao et al.	5,977,251	November 2, 1999
Tanizaki et al.	5,998,039	December 7, 1999
Stevens et al.	6,013,819	January 11, 2000
Nickias et al.	6,015,868	January 18, 2000
Wilson et al.	6,034,021	March 7, 2000
LaPointe	6,034,240	March 7, 2000

U.S. PATENTS AND PUBLISHED APPLICATIONS

<u>Inventor(s)</u>	<u>Patent/Application No.</u>	<u>Issue/Publication Date</u>
LaPointe et al.	6,043,363	March 28, 2000
Rosen et al.	6,074,977	June 13, 2000
Murray	6,103,657	August 15, 2000
Campbell, Jr. et al.	6,150,297	November 21, 2000
Chatterjee et al.	6,197,886	March 6, 2001
Kaufman et al.	6,245,856	June 12, 2001
Fisher et al.	6,248,829	June 19, 2001
Klosin et al.	6,268,444	July 31, 2001
Murray et al.	6,303,719	October 16, 2001
Wouters	6,372,847	April 16, 2002
Klosin et al.	6,515,155	February 4, 2003
Datta et al.	6,642,316	November 4, 2003
Cozewith et al.	2002/0004575	January 10, 2002
Campbell, Jr. et al.	2002/0062011	May 23, 2002
Boussie et al.	2002/0137845	September 26, 2002
Boussie et al.	2002/0142912	October 3, 2002
Boussie et al.	2002/0147288	October 10, 2002
Boussie et al.	2002/0156279	October 24, 2002
Klosin et al.	2002/0165329	November 7, 2002
Boussie et al.	2002/0173419	November 21, 2002
LaPointe et al.	2002/0177711	November 28, 2002
Klosin et al.	2003/0004286	January 2, 2003

FOREIGN PATENT DOCUMENTS

<u>Country</u>	<u>Document No.</u>	<u>Date</u>
WO	88/05792 A1	August 11, 1988
WO	88/05793 A1	August 11, 1988
WO	90/2001521 A1	February 22, 1990
WO	90/07526 A1	July 12, 1990
WO	93/11171	June 10, 1993
WO	93/18106	September 16, 1993
WO	93/19104 A1	September 30, 1993
WO	93/21238 A3	October 28, 1993
WO	93/21238 A2	October 28, 1993
WO	93/21242 A1	October 28, 1993
WO	93/25590 A1	December 23, 1993
WO	94/2000500 A1	January 6, 1994

FOREIGN PATENT DOCUMENTS

<u>Country</u>	<u>Document No.</u>	<u>Date</u>
WO	94/2003506 A1	February 17, 1994
WO	94/25495	November 10, 1994
WO	94/25497	November 10, 1994
WO	94/26793	November 24, 1994
WO	94/28032	December 8, 1994
WO	94/29032	December 22, 1994
WO	95/2000526 A1	January 5, 1995
WO	95/07942	March 23, 1995
WO	95/13305 A1	May 18, 1995
WO	95/13306 A1	May 18, 1995
WO	96/2000244 A1	January 4, 1996
WO	96/13530 A1	May 9, 1996
WO	96/23010 A2	August 1, 1996
WO	97/22635 A1	June 26, 1997
WO	97/25355	July 17, 1997
WO	97/42241 A1	November 13, 1997
WO	98/41529 A1	September 24, 1998
WO	98/50392 A1	November 12, 1998
WO	99/14250 A1	March 25, 1999
WO	00/2001745 A1	January 13, 2000
EPO	0 229 476	July 22, 1987
EPO	EP 0 277 003 A1	August 3, 1988
EPO	EP 0 468 537 A1	January 29, 1992
EPO	EP 0 468 651 A1	January 29, 1992
EPO	EP 0 514 828 A1	November 25, 1992
EPO	EP 0 515 203 A2	November 25, 1992
EPO	EP 0 515 203 A3	November 25, 1992
EPO	EP 0 593 083 A1	April 20, 1994
EPO	EP 0 628 343 A1	December 14, 1994
EPO	EP 0 659 773 A1	June 28, 1995
EPO	EP 0 663 422 A2	July 19, 1995
EPO	EP 0 676 421 A1	October 11, 1995
EPO	EP 0 683 176 A1	November 22, 1995
EPO	EP 0 692 500 B1	January 17, 1996
EPO	EP 0 697 420 A1	February 21, 1996
EPO	EP 0 699 213 B1	March 6, 1996
EPO	EP 0 716 121 A1	June 12, 1996
EPO	EP 0 721 798 A3	January 2, 1997
EPO	EP 0 721 798 A2	July 17, 1996

FOREIGN PATENT DOCUMENTS

<u>Country</u>	<u>Document No.</u>	<u>Date</u>
EPO	EP 0 728 150 B1	August 28, 1996
EPO	EP 0 728 151 B1	August 28, 1996
EPO	EP 0 728 771 A1	August 28, 1996
EPO	EP 0 728 772 A1	August 28, 1996
EPO	EP 0 735 058 A1	October 2, 1996
EPO	EP 0 748 846 A2	December 18, 1996
EPO	EP 0 748 846 A3	February 12, 1997
EPO	EP 0 780 404 A3	December 29, 1997
EPO	EP 0 780 404 A2	June 25, 1997
EPO	EP 0 844 280 A1	May 27, 1998
EPO	EP 0 949 278 A3	September 13, 2000
EPO	EP 0 949 278 A2	October 13, 1999
EPO	EP 0 949 279 A3	September 13, 2000
EPO	EP 0 949 279 A2	October 13, 1999
EPO	EP 1 063 244 A2	December 27, 2000

OTHER DOCUMENTS

News Release, Japan Polychem Launches WINTEC Metallocene-Based PP Random Copolymer, October 25, 2001, <http://www.m-kagaku.co.jp/english/rel/2001/102501.htm>.

Product Sample Report for Escorene 4292, Polymer Science Laboratory of the Baytown Polymer Center, Exxon Chemical, May 9, 2000.

Alt, Helmut G., et al., *Chem. Rev.*, 2000, 100, 1205-1221.

Brintzinger, Hans H., et al, *Angew Chem. Int. Ed. Engl.*, 1995, 34, 1143-1170.

Chen, Eugene You-Xian, et al., *Chem. Rev.*, 2000, 100, 1391-1434.

Coates, Geoffrey W., *Chem. Rev.*, 2000, 100, 1223-1252.

Hazlitt, Lonnie G., *Journal of Applied Polymer Science: Applied Power Symposium*, 1990, 45, 25-37.

Herzog, Timothy A., et al., *J. Am. Chem. Soc.*, 1996, 118, 11988-11989.

Ittel, Steven D., et al., *Chem. Rev.*, 2000, 100, 1169-1203.

The Encyclopedia of Chemical Technology, Kirk-Othmer, Third Edition, John Wiley & Sons, New York, 1981, Vol. 16, pp. 415-417.

The Encyclopedia of Chemical Technology, Kirk-Othmer, Third Edition, John Wiley & Sons, New York, 1981, Vol. 18, pp. 191-192.

Lambert, Joseph B., et al., *J. Chem. Soc., Chem. Commun.*, 1993, 383-384.

Mathur, Naresh C. et al., *Tetrahedron*, 1985, Vol. 41, No. 8, 1509-1516.

Otocka, E.P., et al., *Macromolecules*, July-August 1971, Vol. 4, No. 4, 507-514.

Randall, James C., *JMS-Rev. Macromol. Chem. Phys.*, 1989, C29(2 & 3), 201-317.

Resconi, Luigi, et al., *Chem. Rev.* 2000, 100, 1253-1345.

Scholte, Th. G., et al., *Journal of Applied Polymer Science*, 1984, Vol. 29, 3763-3782.

Scollard, John D., et al., *J. Am. Chem. Soc.* 1996, 118, 10008-10009.

Veghini, Dario, et al., *J. Am. Chem. Soc.* 1999, 121, 564-573.

Wang, Chunming, et al., *Organometallics*, 1998, Vol. 17, No. 15, 3149-3151.

Wild, L. et al., *Journal of Polymer Science Polymer Physics Edition*, 1982, Vol. 20, 441-455.

Younkin, Todd R., et al., *Science*, 2000, Vol. 287, Issue 5452, 460-462.

Pursuant to 37 C.F.R. §§ 1.56 and 1.97, Applicants also make of record the following documents that were not initialed by the Examiner in the Information Disclosure Statement previously filed in the above-identified application on January 20, 2004:

FOREIGN PATENT DOCUMENTS

EPO	EP 0 480 190 B1	April 15, 1992	(abstract only)
EPO	EP 0 890 584 A1	January 13, 1999	(abstract only)

OTHER DOCUMENTS

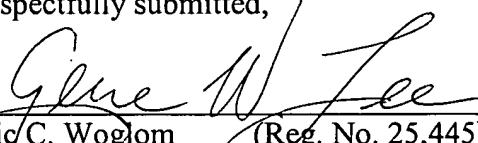
- ASTM D 1646-96a – “Standard Test Methods for Rubber – Viscosity, Stress Relaxation, and Pre-vulcanization Characteristics (Mooney Viscometer),” *American Society for Testing & Materials, Annual Book of ASTM Standards*, 1997, Vol. 09.01, 313-322.
- ASTM D 3900-95 – “Standard Test Methods for Rubber Raw –Determination of Ethylene Units in EPM (Ethylene-Propylene Copolymers) and EPDM (Ethylene-Propylene-Diene Terpolymers),” *American Society for Testing & Materials, Annual Book of ASTM Standards*, 1997, Vol. 09.01, 616-624.
- H.N. Cheng, “ ^{13}C NMR Analysis of Ethylene-Propylene Rubbers,” *Macromolecules*, 1984, Vol. 17, 1950-1955.
- G. Ver Strate et al., “Near Monodisperse Ethylene-Propylene Copolymers by Direct Ziegler-Natta Polymerization Properties, Characterization, Properties,” *Macromolecules*, 1988, Vol. 21, 3360-3371.
- J.W. Collette et al., “Elastomeric Polypropylenes from Alumina-Supported Tetraalkyl Group IVB Catalysts. 1. Synthesis and Properties of High Molecular Weight Stereoblock Hopolymers,” *Macromolecules*, 1989, Vol. 22, 3851-3858.
- W.J. Gauthier et al., “Elastomeric Poly(propylene): Influence of Catalyst Structure and Polymerization Conditions on Polymer Structure and Properties,” *Macromolecules*, 1995, Vol. 28, 3771-3778.
- Y. Hu et al., “Elastomeric Polypropylenes from Unbridged (2-Phenylindene)-zirconocene Catalysts: Thermal Characterization and Mechanical Properties,” *Macromolecules*, 1998, Vol. 31, 6908-6916.
- J. Chien et al., “Two-State Propagation Mechanism for Propylene Polymerization Catalyzed by *rac*-[*anti*-Ethylidene(1- η^5 -tetramethylcyclopentadienyl)(1- η^5 -indenyl)dimethyltitanium],” *Journal of the American Chemical Society*, 1991, Vol. 113, 8569-8570.
- E. Hauptman et al., “Stereoblock Polypropylene: Ligand Effects on the Stereospecificity of 2-Arylindene Zirconocene,” *Journal of the American Chemical Society*, 1995, Vol. 117, 11586-11587.
- M.D. Bruce et al., “Effect of Metal on the Stereospecificity of 2-Arylindene Catalysts for Elastomeric Polypropylene,” *Journal of the American Chemical Society*, 1997, Vol. 119, 11174-11182.

- I. Tincul et al., "Impact Fracture Toughness of Propylene/1-Pentene Random Copolymers," *Proceedings of the American Chemical Society Division of Polymeric Materials: Science and Engineering*, 1998, 79, 190-191.

All of the aforementioned documents are listed on the accompanying Form PTO-1449 (submitted in duplicate). Pursuant to the U.S. Patent and Trademark Office's waiver of the requirement under 35 C.F.R. § 1.98(a)(2)(i) for all U.S. national patent applications filed after June 30, 2003, copies of issued U.S. patents and published U.S. patent applications are not provided. Copies of all foreign patent documents and all other documents cited above are provided.

It is respectfully requested that these documents be (1) fully considered by the Patent and Trademark Office during examination of this application; and (2) printed on any patent which may issue on this application. Applicants request that a copy of Form PTO-1449, as considered and initialed by the Examiner, be returned with the next communication.

Respectfully submitted,


Eric C. Woglom (Reg. No. 25,445)
Glenn A. Ousterhout (Reg. No. 30,410)
Gene W. Lee (Reg. No. 55,369)
Attorneys for Applicants
Wendy A. Petka (Reg. No. 53,459)
Agent for Applicants
c/o FISH & NEAVE LLP
Customer No. 1473
1251 Avenue of the Americas
New York, New York 10020-1104
Tel.: (212) 596-9000

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
1998B037A/2APPLN NO.
10/613,374INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANTS
S. Datta et al.CONFIRMATION
NO. 7178FILING DATE
July 3, 2003GROUP ART UNIT
1711

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	3520861	07/21/70	Thomson et al.	260	88.1	
	4076698	02/28/78	Anderson et al.	526	348.6	
	4542199	09/17/85	Kaminsky et al.	526	160	
	4543399	09/24/85	Jenkins, III et al.	526	70	
	4544762	10/01/85	Kaminsky et al.	556	179	
	4588790	05/13/86	Jenkins, III et al.	526	70	
	4599392	07/08/86	McKinney et al.	526	318.6	
	4874880	10/17/89	Miya et al.	556	53	
	4960878	10/02/90	Crapo et al.	556	179	
	4988781	01/29/91	McKinney et al.	526	68	
	5015749	05/14/91	Schmidt et al.	556	179	
	5028670	07/02/91	Chinh et al.	526	73	
	5032562	07/16/91	Lo et al.	502	111	
	5041583	08/20/91	Sangokoya	556	179	
	5041584	08/20/91	Crapo et al.	556	179	
	5041585	08/20/91	Deavenport et al.	556	179	
	5044438	09/03/91	Young	166	250	
	5057475	10/15/91	Canich et al.	502	104	
	5064802	11/12/91	Stevens et al.	502	155	
	5093415	03/03/92	Brady, III et al.	525	53	
	5096867	03/17/92	Canich	502	103	
	5106804	04/21/92	Bailly et al.	502	108	
	5132380	07/21/92	Stevens et al.	526	126	
	5134209	07/28/92	Job et al.	526	141	
	5153157	10/06/92	Hlatky et al.	502	117	
	5198401	03/30/93	Turner et al.	502	155	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
1998B037A/2APPLN NO.
10/613,374INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANTS
S. Datta et al.CONFIRMATION
NO. 7178FILING DATE
July 3, 2003GROUP ART UNIT
1711

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5218071	06/08/93	Tsutsui et al.	526	348	
	5272236	12/21/93	Lai et al.	526	348.5	
	5278272	01/11/94	Lai et al.	526	348.5	
	5296433	03/22/94	Siedle et al.	502	117	
	5324800	06/28/94	Welborn, Jr. et al.	526	160	
	5350723	09/27/94	Neithamer et al.	502	104	
	5352749	10/04/94	DeChellis et al.	526	68	
	5384373	01/24/95	McKinney et al.	526	212	
	5405922	04/11/95	DeChellis et al.	526	68	
	5408017	04/18/95	Turner et al.	526	134	
	5427991	06/27/95	Turner	502	103	
	5436304	07/25/95	Griffin et al.	526	68	
	5453471	03/26/95	Bernier et al.	526	68	
	5461123	10/24/95	Song et al.	526	74	
	5462999	10/31/95	Griffin et al.	526	68	
	5473028	12/05/95	Nowlin et al.	526	114	
	5504049	04/02/96	Crowther et al.	502	117	
	5504172	04/02/96	Imuta et al.	526	351	
	5541270	07/30/96	Chinh et al.	526	68	
	5556238	09/17/96	Chinh	406	136	
	5556928	09/17/96	Devore et al.	526	127	
	5599761	02/04/97	Turner	502	152	
	5608019	03/04/97	Cheruvu et al.	526	129	
	5616661	04/01/97	Eisinger et al.	526	88	
	5616664	04/01/97	Timmers et al.	526	127	
	5621127	04/15/97	Langhauser et al.	556	11	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

1998B037A/2

APPLN NO.

10/613,374

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

APPLICANTS

S. Datta et al.

CONFIRMATION
NO. 7178

FILING DATE

July 3, 2003

GROUP ART UNIT

1711

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5625087	04/29/97	Devore et al.	556	468	
	5637660	06/10/97	Nagy et al.	526	160	
	5685128	11/11/97	Chum et al.	53	441	
	5703187	12/30/97	Timmers	526	282	
	5703257	12/30/97	Rosen et al.	556	7	
	5710224	01/20/98	Alt et al.	526	160	
	5721185	02/24/98	LaPointe et al.	502	117	
	5728855	03/17/98	Smith et al.	556	179	
	5731253	03/24/98	Sangokoya	502	102	
	5767208	06/16/98	Turner et al.	526	160	
	5840389	11/24/98	Asanuma et al.	428	36.91	
	5874505	02/23/99	Saito et al.	525	240	
	5883188	03/16/99	Hwang et al.	525	71	
	5883204	03/16/99	Spencer et al.	526	134	
	5907021	05/25/99	Turner et al.	526	160	
	5919983	07/06/99	Rosen et al.	568	3	
	5962714	10/05/99	McCullough et al.	556	11	
	5965677	10/12/99	Stephan et al.	526	129	
	5965756	10/12/99	McAdon et al.	556	11	
	5972822	10/26/99	Timmers et al.	502	103	
	5977251	11/02/99	Kao et al.	525	53	
	5998039	12/07/99	Tanizaki et al.	428	516	
	6013819	01/11/00	Stevens et al.	556	11	
	6015868	01/18/00	Nickias et al.	526	127	
	6034021	03/07/00	Wilson et al.	502	103	
	6034240	03/07/00	LaPointe	546	24	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 1998B037A/2	APPLN NO. 10/613,374
	APPLICANTS S. Datta et al.	CONFIRMATION NO. 7178
	FILING DATE July 3, 2003	GROUP ART UNIT 1711

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6043363	03/28/00	LaPointe et al.	544	225	
	6074977	06/13/00	Rosen et al.	502	103	
	6103657	08/15/00	Murray	502	155	
	6150297	11/21/00	Campbell, Jr. et al.	502	152	
	6197886	03/06/01	Chatterjee et al.	525	240	
	6245856	06/12/01	Kaufman et al.	525	240	
	6248829	06/19/01	Fisher et al.	525	191	
	6268444	07/31/01	Klosin et al.	526	127	
	6303719	10/16/01	Murray et al.	526	161	
	6372847	04/16/02	Wouters	525	191	
	6515155	02/04/03	Klosin et al.	556	11	
	664236	11/04/03	Datta et al.	525	240	
	20020004575	01/10/02	Cozewith et al.	526	348	
	20020062011	05/23/02	Campbell, Jr. et al.	534	15	
	20020137845	09/26/02	Boussie et al.	525	170	
	20020142912	10/03/02	Boussie et al.	502	152	
	20020147288	10/10/02	Boussie et al.	526	160	
	20020156279	10/24/02	Boussie et al.	546	13	
	20020165329	11/07/02	Klosin et al.	526	126	
	20020173419	11/21/02	Boussie et al.	502	117	
	20020177711	11/28/02	LaPointe et al.	546	13	
	20030004286	01/02/03	Klosin et al.	526	126	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
1998B037A-2 RCEAPPLN NO.
10/613,374INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANTS
S. Datta et al.CONFIRMATION
NO. 7178FILING DATE
July 3, 2003GROUP ART UNIT
1711

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	88/05792 A1	08/11/88	WO	C08F	4/64		
	88/05793 A1	08/11/88	WO	C08F	4/64		
	90/01521 A1	02/22/90	WO	C08L	67/04		
	90/07526 A1	07/12/90	WO	C08F	10/00		
	93/11171	06/10/93	WO	C08F	10/00		
	93/18106	09/16/93	WO	C09J	123/16		
	93/19104 A1	09/30/93	WO	C08F	10/00		
	93/21238 A3	10/28/93	WO	C08F	10/00		
	93/21238 A2	10/28/93	WO	C08F	10/00		
	93/21242 A1	10/28/93	WO	C08F	210/16		
	93/25590 A1	12/23/93	WO	C08F	10/00		
	94/00500 A1	01/06/94	WO	C08F	10/00		
	94/03506 A1	02/17/94	WO	C08F	4/64		
	94/25495	11/10/94	WO	C08F	2/34		
	94/25497	11/10/94	WO	C08F	10/00		
	94/26793	11/24/94	WO	C08F	10/00		
	94/28032	12/08/94	WO	C08F	2/34		
	94/29032	12/22/94	WO	B05B	7/16		
	95/00526 A1	01/05/95	WO	C07F	17/00		
	95/07942	03/23/95	WO	C08F	10/02		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

1998B037A-2 RCE

APPLN NO.

10/613,374

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

APPLICANTS

S. Datta et al.

CONFIRMATION

NO. 7178

FILING DATE

July 3, 2003

GROUP ART UNIT

1711

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	95/13305 A1	05/18/95	WO	C08F	2/34		
	95/13306 A1	05/18/95	WO	C08F	2/34		
	96/00244 A1	01/04/96	WO	C08F	10/00		
	96/13530 A1	05/09/96	WO	C08F	10/00		
	96/23010 A2	08/01/96	WO	C08F	210/16		
	97/22635 A1	06/26/97	WO	C08F	10/00		
	97/25355	07/17/97	WO	C08F	10/00		
	97/42241 A1	11/13/97	WO	C08F	212/04		
	98/50392 A1	11/12/98	WO	C07F	9/6568		
	98/41529 A1	09/24/98	WO	C07F	17/00		
	99/14250 A1	03/25/99	WO	C08F	10/00		
	00/01745 A1	01/13/00	WO	C08F	210/16		
	EP 0 229 476	07/22/87	EPO	B32B	27/32		
	EP 0 277 003 A1	08/03/88	EPO	C08F	4/64		
	EP 0 468 537 A1	01/29/92	EPO	C08F	10/00		
	EP 0 468 651 A1	01/29/92	EPO	C08F	4/74		
	EP 0 514 828 A1	11/25/92	EPO	C07F	7/28		
	EP 0 515 203 A2	11/25/92	EPO	C08L	67/04		
	EP 0 515 203 A3	11/25/92	EPO	C08L	67/04		
	EP 0 593 083 A1	04/20/94	EPO	C08F	2/34		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
1998B037A-2 RCEAPPLN NO.
10/613,374INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANTS
S. Datta et al.CONFIRMATION
NO. 7178FILING DATE
July 3, 2003GROUP ART UNIT
1711

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	EP 0 628 343 A1	12/14/94	EPO	B01J	3/02		
	EP 0 659 773 A1	06/28/95	EPO	C08F	10/00		
	EP 0 663 422 A2	07/19/95	EPO	C08L	23/06		
	EP 0 676 421 A1	10/11/95	EPO	C08F	10/02		
	EP 0 683 176 A1	11/22/95	EPO	C08F	6/00		
	EP 0 692 500 B1	01/17/96	EPO	C08F	210/00		
	EP 0 697 420 A1	02/21/96	EPO	C08F	10/06		
	EP 0 699 213 B1	03/06/96	EPO	C08F	2/34		
	EP 0 716 121 A1	06/12/96	EPO	C08L	23/10		
	EP 0 721 798 A3	01/02/97	EPO	B01J	8/44		
	EP 0 721 798 A2	07/17/96	EPO	B01J	8/44		
	EP 0 728 150 B1	08/28/96	EPO	C08F	2/34		
	EP 0 728 151 B1	08/28/96	EPO	C08F	2/34		
	EP 0 728 771 A1	08/28/96	EPO	C08F	10/00		
	EP 0 728 772 A1	08/28/96	EPO	C08F	10/00		
	EP 0 735 058 A1	10/02/96	EPO	C08F	10/00		
	EP 0 748 846 A2	12/18/96	EPO	C08L	67/04		
	EP 0 748 846 A3	02/12/97	EPO	C08L	67/04		
	EP 0 780 404 A3	12/29/97	EPO	C08F	10/02		
	EP 0 780 404 A2	06/25/97	EPO	C08F	10/02		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
1998B037A-2 RCEAPPLN NO.
10/613,374INFORMATION DISCLOSURE
STATEMENT BY APPLICANTAPPLICANTS
S. Datta et al.CONFIRMATION
NO. 7178FILING DATE
July 3, 2003GROUP ART UNIT
1711

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	EP 0 844 280 A1	05/27/98	EPO	C08L	23/10		
	EP 0 949 278 A3	09/13/00	EPO	C08F	10/00		
	EP 0 949 278 A2	10/13/99	EPO	C08F	10/00		
	EP 0 949 279 A3	09/13/00	EPO	C08F	10/00		
	EP 0 949 279 A2	10/13/99	EPO	C08F	10/00		
	EP 1 063 244 A2	12/27/00	EPO	C08F	210/18		
	EP 0 480 190 B1	06/07/95	EPO	C08F	10/06	X (abstract only)	
	EP 0 890 584 A1	04/15/92	EPO	C08F	10/06	X (abstract only)	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

1998B037A-2 RCE

APPLN NO.

10/613,374

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

APPLICANTS

S. Datta et al.

CONFIRMATION
NO. 7178

FILING DATE

July 3, 2003

GROUP ART UNIT

1711

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER
INITIAL

	News Release, Japan Polychem Launches WINTEC Metallocene-Based PP Random Copolymer, October 25, 2001, http://www.m-kagaku.co.jp/english/rel/2001/102501.htm .
	Alt, Helmut G., et al., <i>Chem. Rev.</i> , 2000, 100, 1205-1221.
	Brintzinger, Hans H., et al., <i>Angew Chem. Int. Ed. Engl.</i> , 1995, 34, 1143-1170.
	Chen, Eugene You-Xian, et al., <i>Chem. Rev.</i> , 2000, 100, 1391-1434.
	Coates, Geoffrey W., <i>Chem. Rev.</i> , 2000, 100, 1223-1252.
	Hazlitt, Lonnie G., <i>Journal of Applied Polymer Science: Applied Power Symposium</i> , 1990, 45, 25-37.
	Herzog, Timothy A., et al., <i>J. Am. Chem. Soc.</i> , 1996, 118, 11988-11989.
	Ittel, Steven D., et al., <i>Chem. Rev.</i> , 2000, 100, 1169-1203.
	<i>The Encyclopedia of Chemical Technology</i> , Kirk-Othmer, Third Edition, John Wiley & Sons, New York, 1981, Vol. 16, 415-417.
	<i>The Encyclopedia of Chemical Technology</i> , Kirk-Othmer, Third Edition, John Wiley & Sons, New York, 1981, Vol. 18, 191-192.
	Lambert, Joseph B., et al., <i>J. Chem. Soc., Chem. Commun.</i> , 1993, 383-384.
	Mathur, Naresh C. et al., <i>Tetrahedron</i> , 1985, Vol. 41, No. 8, 1509-1516.
	Otocka, E.P., et al., <i>Macromolecules</i> , July-August 1971, Vol. 4, No. 4, 507-514.
	Randall, James C., <i>JMS-Rev. Macromol. Chem. Phys.</i> , 1989, C29(2 & 3), 201-317.
	Resconi, Luigi, et al., <i>Chem. Rev.</i> , 2000, 100, 1253-1345.
	Scholte, Th. G., et al., <i>Journal of Applied Polymer Science</i> , 1984, Vol. 29, 3763-3782.
	Scollard, John D., et al., <i>J. Am. Chem. Soc.</i> , 1996, 118, 10008-10009.
	Veghini, Dario, et al., <i>J. Am. Chem. Soc.</i> , 1999, 121, 564-573.
	Wang, Chunming, et al., <i>Organometallics</i> , 1998, Vol. 17, No. 15, 3149-3151.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

1998B037A-2 RCE

APPLN NO.

10/613,374

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

APPLICANTS

S. Datta et al.

CONFIRMATION
NO. 7178

FILING DATE

July 3, 2003

GROUP ART UNIT

1711

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER
INITIAL

	Wild, L. et al., <i>Journal of Polymer Science Polymer Physics Edition</i> , 1982, Vol. 20, 441-455.
	Younkin, Todd R., et al., <i>Science</i> , 2000, Vol. 287, Issue 5452, 460-462.
	Product Sample Report for Escorene PP 4292, Polymer Science Laboratory of the Baytown Polymer Center, Exxon Chemical, May 9, 2000.
	ASTM D 1646-96a – "Standard Test Methods for Rubber – Viscosity, Stress Relaxation, and Pre-vulcanization Characteristics (Mooney Viscometer)," <i>American Society for Testing & Materials, Annual Book of ASTM Standards</i> , 1997, Vol. 09.01, 313-322.
	ASTM D 3900-95 – "Standard Test Methods for Rubber Raw –Determination of Ethylene Units in EPM (Ethylene-Propylene Copolymers) and EPDM (Ethylene-Propylene-Diene Terpolymers)," <i>American Society for Testing & Materials, Annual Book of ASTM Standards</i> , 1997, Vol. 09.01, 616-624.
	H.N. Cheng, " ¹³ C NMR Analysis of Ethylene-Propylene Rubbers," <i>Macromolecules</i> , 1984, Vol. 17, 1950-1955.
	G. Ver Strate et al., "Near Monodisperse Ethylene-Propylene Copolymers by Direct Ziegler-Natta Polymerization Properties, Characterization, Properties," <i>Macromolecules</i> , 1988, Vol. 21, 3360-3371.
	J.W. Collette et al., "Elastomeric Polypropylenes from Alumina-Supported Tetraalkyl Group IVB Catalysts. 1. Synthesis and Properties of High Molecular Weight Stereoblock Hopolymers," <i>Macromolecules</i> , 1989, Vol. 22, 3851-3858.
	W.J. Gauthier et al., "Elastomeric Poly(propylene): Influence of Catalyst Structure and Polymerization Conditions on Polymer Structure and Properties," <i>Macromolecules</i> , 1995, Vol. 28, 3771-3778.
	Y. Hu et al., "Elastomeric Polypropylenes from Unbridged (2-Phenylindene)-zirconocene Catalysts: Thermal Characterization and Mechanical Properties," <i>Macromolecules</i> , 1998, Vol. 31, 6908-6916.
	J. Chien et al., "Two-State Propagation Mechanism for Propylene Polymerization Catalyzed by <i>rac</i> -[<i>anti</i> -Ethylidene(1- η^5 -tetramethylcyclo-pentadienyl)(1- η^5 -indenyl)dimethyltitanium]," <i>Journal of the American Chemical Society</i> , 1991, Vol. 113, 8569-8570.
	E. Hauptman et al., "Stereoblock Polypropylene: Ligand Effects on the Stereospecificity of 2-Arylindene Zirconocene," <i>Journal of the American Chemical Society</i> , 1995, Vol. 117, 11586-11587.
	M.D. Bruce et al., "Effect of Metal on the Stereospecificity of 2-Arylindene Catalysts for Elastomeric Polypropylene," <i>Journal of the American Chemical Society</i> , 1997, Vol. 119, 11174-11182.
	I. Tincul et al., "Impact Fracture Toughness of Propylene/1-Pentene Random Copolymers," <i>Proceedings of the American Chemical Society Division of Polymeric Materials: Science and Engineering</i> , 1998, 79, 190-191.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.